

Important notice

Dear Customer,

On 7 February 2017 the former NXP Standard Product business became a new company with the tradename **Nexperia**. Nexperia is an industry leading supplier of Discrete, Logic and PowerMOS semiconductors with its focus on the automotive, industrial, computing, consumer and wearable application markets

In data sheets and application notes which still contain NXP or Philips Semiconductors references, use the references to Nexperia, as shown below.

Instead of http://www.nxp.com, http://www.nxp.com, http://www.nexperia.com, http://www.nexperia.com)

Instead of sales.addresses@www.nxp.com or sales.addresses@www.semiconductors.philips.com, use salesaddresses@nexperia.com (email)

Replace the copyright notice at the bottom of each page or elsewhere in the document, depending on the version, as shown below:

- © NXP N.V. (year). All rights reserved or © Koninklijke Philips Electronics N.V. (year). All rights reserved

Should be replaced with:

- © Nexperia B.V. (year). All rights reserved.

If you have any questions related to the data sheet, please contact our nearest sales office via e-mail or telephone (details via **salesaddresses@nexperia.com**). Thank you for your cooperation and understanding,

Kind regards,

Team Nexperia

Ultra low capacitance bidirectional quadruple ESD protection arrays

Rev. 01 — 15 August 2008

Product data sheet

1. Product profile

1.1 General description

Ultra low capacitance bidirectional quadruple ElectroStatic Discharge (ESD) protection arrays in ultra small Surface-Mounted Device (SMD) plastic packages designed to protect up to four signal lines from the damage caused by ESD and other transients.

Table 1. Product overview

Type number	Package		Package configuration
	NXP	JEDEC	
PESD5V0U4BF	SOT886	MO-252	leadless ultra small
PESD5V0U4BW	SOT665	-	ultra small and flat lead

1.2 Features

- Bidirectional ESD protection of up to four lines
- Ultra low diode capacitance: C_d = 2.9 pF IEC 61000-4-2; level 4 (ESD)

ESD protection up to 10 kV

- Ultra low leakage current: I_{RM} = 5 nA
- AEC-Q101 qualified

1.3 Applications

- Computers and peripherals
- Audio and video equipment
- Cellular handsets and accessories
- 10/100/1000 Mbit/s Ethernet
- Communication systems

- Portable electronics
- Subscriber Identity Module (SIM) card protection
- FireWire
- High-speed data lines



Ultra low capacitance bidirectional quadruple ESD protection arrays

1.4 Quick reference data

Quick reference data

 $T_{amb} = 25 \,^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per diode						
V_{RWM}	reverse standoff voltage		-	-	5	V
C_d	diode capacitance	$f = 1 MHz; V_R = 0 V$	-	2.9	3.5	pF

Pinning information

Table 3. **Pinning** Pin Description Simplified outline **Graphic symbol** PESD5V0U4BF 1 cathode (diode 1) 2 common cathode 3 cathode (diode 2) 4 cathode (diode 3) KIDI KIDI 5 common cathode 6 cathode (diode 4) 006aab333 bottom view PESD5V0U4BW 1 cathode (diode 1) 2 common cathode 3 cathode (diode 2) 4 cathode (diode 3) 5 cathode (diode 4)

Ordering information 3.

Product data sheet

Table 4. **Ordering information**

Type number	Package		
	Name	Description	Version
PESD5V0U4BF	XSON6	plastic extremely thin small outline package; no leads; 6 terminals; body 1 \times 1.45 \times 0.5 mm	SOT886
PESD5V0U4BW	-	plastic surface-mounted package; 5 leads	SOT665

006aab334

2 of 12

PESD5V0U4BF PESD5V0U4BW 1 © NXP B.V. 2008. All rights reserved. Rev. 01 — 15 August 2008

Ultra low capacitance bidirectional quadruple ESD protection arrays

Marking 4.

Product data sheet

Table 5. **Marking codes**

Type number	Marking code
PESD5V0U4BF	B1
PESD5V0U4BW	A6

Limiting values 5.

Table 6. **Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
Per device					
Tj	junction temperature		-	150	°C
T _{amb}	ambient temperature		-55	+150	°C
T _{stg}	storage temperature		-65	+150	°C

Table 7. **ESD** maximum ratings

 T_{amb} = 25 °C unless otherwise specified.

Symbol	Parameter	Conditions		Min	Max	Unit
Per diode	•					
V _{ESD}	electrostatic discharge voltage		<u>[1]</u>			
	PESD5V0U4BF	IEC 61000-4-2 (contact discharge)	[2]	-	10	kV
	PESD5V0U4BW	IEC 61000-4-2 (contact discharge)	[3]	-	10	kV
	PESD5V0U4BF	MIL-STD-883 (human body model)	[2]	-	8	kV
	PESD5V0U4BW	MIL-STD-883 (human body model)	[3]	-	8	kV

^[1] Device stressed with ten non-repetitive ESD pulses.

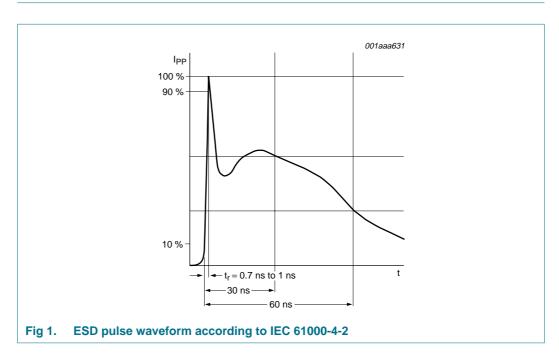
Measured from pin 1, 3, 4 or 5 to pin 2.

Measured from pin 1, 3, 4 or 6 to pin 2 or 5.

Ultra low capacitance bidirectional quadruple ESD protection arrays

Table 8. ESD standards compliance

Standard	Conditions
Per diode	
IEC 61000-4-2; level 4 (ESD)	> 15 kV (air); > 8 kV (contact)
MIL-STD-883; class 3 (human body model)	> 4 kV



Product data sheet Rev. 01 — 15 August 2008 4 of 12

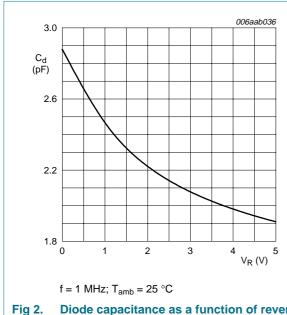
Ultra low capacitance bidirectional quadruple ESD protection arrays

Characteristics 6.

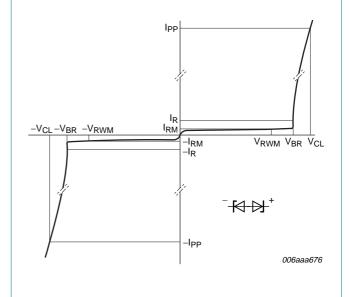
Table 9. **Characteristics**

T_{amb} = 25 °C unless otherwise specified.

Symbol	Parameter	Conditions	Mi	n Ty	o Max	Unit
Per diod	е					
V_{RWM}	reverse standoff voltage		-	-	5	V
I _{RM}	reverse leakage current	$V_{RWM} = 5 V$	-	5	100	nA
V_{BR}	breakdown voltage	$I_R = 5 \text{ mA}$	5.5	6.5	9.5	V
C_d	diode capacitance	f = 1 MHz				
		$V_R = 0 V$	-	2.9	3.5	pF
		$V_R = 5 V$	-	1.9	-	pF
r _{dif}	differential resistance	$I_R = 1 \text{ mA}$	-	-	100	Ω



Product data sheet



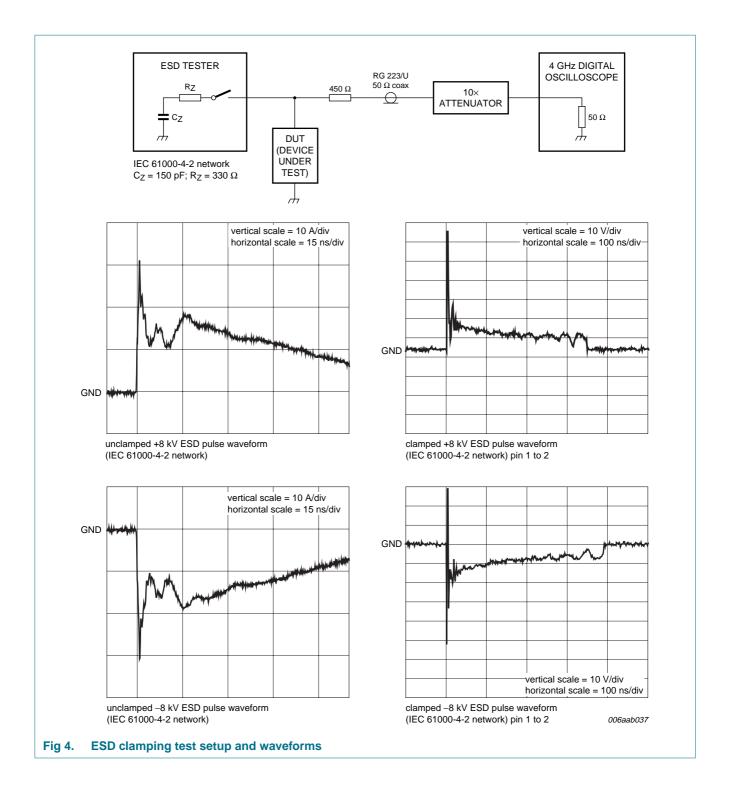
Diode capacitance as a function of reverse voltage; typical values

V-I characteristics for a bidirectional Fig 3. **ESD** protection diode

5 of 12

PESD5V0U4BF_PESD5V0U4BW_1 © NXP B.V. 2008. All rights reserved. Rev. 01 — 15 August 2008

Ultra low capacitance bidirectional quadruple ESD protection arrays

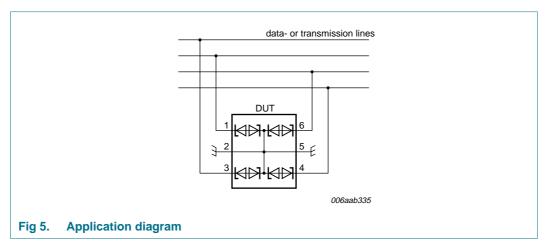


PESD5V0U4BF_PESD5V0U4BW_1 © NXP B.V. 2008. All rights reserved.

Ultra low capacitance bidirectional quadruple ESD protection arrays

7. Application information

The PESD5V0U4BF and the PESD5V0U4BW are designed for the protection of up to four bidirectional data or signal lines from the damage caused by ESD and surge pulses. The devices may be used on lines where the signal polarities are both, positive and negative with respect to ground.



Circuit board layout and protection device placement

Circuit board layout is critical for the suppression of ESD, Electrical Fast Transient (EFT) and surge transients. The following guidelines are recommended:

- 1. Place the device as close to the input terminal or connector as possible.
- 2. The path length between the device and the protected line should be minimized.
- 3. Keep parallel signal paths to a minimum.
- 4. Avoid running protected conductors in parallel with unprotected conductors.
- 5. Minimize all Printed-Circuit Board (PCB) conductive loops including power and ground loops.
- 6. Minimize the length of the transient return path to ground.
- 7. Avoid using shared transient return paths to a common ground point.
- 8. Ground planes should be used whenever possible. For multilayer PCBs, use ground vias.

8. Test information

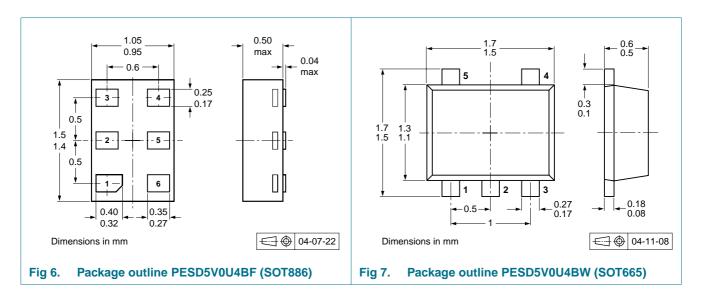
8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

PESD5V0U4BF_PESD5V0U4BW_1 © NXP B.V. 2008. All rights reserved.

Ultra low capacitance bidirectional quadruple ESD protection arrays

Package outline



10. Packing information

Product data sheet

Table 10. Packing methods

The indicated -xxx are the last three digits of the 12NC ordering code.[1]

Type number	Package	Description		ing quai	ntity
			4000	5000	8000
PESD5V0U4BF	SOT886	4 mm pitch, 8 mm tape and reel; T1	1 -	-115	-
		4 mm pitch, 8 mm tape and reel; T4	1 -	-132	-
PESD5V0U4BW	SOT665	2 mm pitch, 8 mm tape and reel	-	-	-315
		4 mm pitch, 8 mm tape and reel	-115	-	-

^[1] For further information and the availability of packing methods, see Section 14.

PESD5V0U4BF_PESD5V0U4BW_1 © NXP B.V. 2008. All rights reserved. Rev. 01 — 15 August 2008

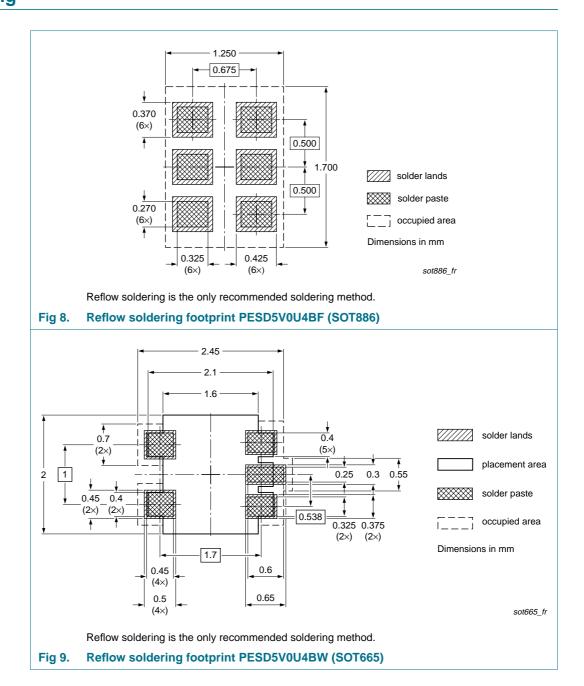
T1: normal taping

T4: 90° rotated reverse taping

Ultra low capacitance bidirectional quadruple ESD protection arrays

11. Soldering

Product data sheet



© NXP B.V. 2008. All rights reserved.

Ultra low capacitance bidirectional quadruple ESD protection arrays

12. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PESD5V0U4BF_PESD5V0U4BW_1	20080815	Product data sheet	-	-

Ultra low capacitance bidirectional quadruple ESD protection arrays

13. Legal information

13.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

13.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

13.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

ESD protection devices — These products are only intended for protection against ElectroStatic Discharge (ESD) pulses and are not intended for any other usage including, without limitation, voltage regulation applications. NXP Semiconductors accepts no liability for use in such applications and therefore such use is at the customer's own risk.

13.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

14. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

PESD5V0U4BF_PESD5V0U4BW_1 © NXP B.V. 2008. All rights reserved.

NXP Semiconductors

PESD5V0U4BF; PESD5V0U4BW

Ultra low capacitance bidirectional quadruple ESD protection arrays

15. Contents

1	Product profile
1.1	General description
1.2	Features
1.3	Applications
1.4	Quick reference data
2	Pinning information
3	Ordering information 2
4	Marking 3
5	Limiting values
6	Characteristics 5
7	Application information 7
8	Test information
8.1	Quality information
9	Package outline 8
10	Packing information 8
11	Soldering 9
12	Revision history
13	Legal information11
13.1	Data sheet status
13.2	Definitions
13.3	Disclaimers
13.4	Trademarks11
14	Contact information11
15	Contents 12

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.



All rights reserved.

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

Date of release: 15 August 2008

Document identifier: PESD5V0U4BF_PESD5V0U4BW_1



单击下面可查看定价,库存,交付和生命周期等信息

>>Nexperia(安世)